## Notice of References Cited

Application/Control No.

10/765,964

Examiner

Daniel S. Metzmaier

Applicant(s)/Patent Under
Reexamination
MINEMURA ET AL.

Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2004/0156809	08-2004	Ono et al.	424/070.12
*	В	US-5,843,335	12-1998	Kurono et al.	516/100
*	ပ	US-5,391,314	02-1995	Minemura et al.	252/78.3
	D	US-			
	ш	US-			
	ш	US-			
	G	US-			
	Н	US-			
	-	US-			
	)	US-			
	K	US-			-
	٦	US-			
	М	US-			4.

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 02/100356 A1	12-2002	WIPO (PCT)	SHIN-ETSU CHEMICAL CO LTD	/
	0	JP 55-115811	09-1980	Japan	SHISEIDO CO LTD	/
	Р	JP 54-28832	03-1979	Japan	SHISEIDO CO LTD	/
	Q					
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	υ	Derwent Abstract on EAST, week 200391, London: Derwent Publications Ltd., AN 1980-74382C, Class A96, JP 55115811 A, (ShISEIDO CO LTD), abstract.
13	٧	Derwent Abstract on EAST, week 200392, London: Derwent Publications Ltd., AN 1979-28586B, Class A26, JP 54028832 A, (SHISEIDO CO LTD), abstract.
	w	
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.